

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	33	(microprobe near4 (assembly system apparatus device machine mechan\$4)).ti.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L2	54	(microprobe near4 (assembly system apparatus device machine mechan\$4)).clm.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L3	8	((microprobe near4 (assembly system apparatus device machine mechan\$4)).clm.) and cantilever	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L4	1768	((("AFM" microcantilever cantilever beam "force detector" "force sensor") and ((static strain stress) near3 (deflection deflect)))	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L5	253	(microprobe near4 (assembly system apparatus device machine mechan\$4))	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L6	1	((microprobe near4 (assembly system apparatus device machine mechan\$4))) and (((("AFM" microcantilever cantilever beam "force detector" "force sensor") and ((static strain stress) near3 (deflection deflect))))	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L7	369	((("AFM" microcantilever cantilever beam "force detector" "force sensor") near6 ((static strain stress) near3 (deflection deflect)))	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L8	48	((("AFM" microcantilever cantilever beam "force detector" "force sensor") near6 ((static strain stress) near3 (deflection deflect))).clm.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L9	18	((("AFM" microcantilever cantilever beam "force detector" "force sensor") near6 ((static strain stress) near3 (deflection deflect))).clm.) and "73"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:48
L10	11076	((deflect\$5 bend\$4 deform\$5) near6 (microprobe probe cantilever microcantilever))	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:49
L11	271	((deflect\$5 bend\$4 deform\$5) near6 (microprobe probe cantilever microcantilever))) and ((compensat\$5 correct\$5) near4 (wedge piece area portion inclin\$6))	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:49
L12	43	((deflect\$5 bend\$4 deform\$5) near6 (microprobe probe cantilever microcantilever))) and ((compensat\$5 correct\$5) near4 (wedge piece area portion inclin\$6))) and "73"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:49
L13	83	((deflect\$5 bend\$4 deform\$5) near6 (beam microprobe probe cantilever microcantilever))) and ((compensat\$5 correct\$5) near4 (wedge piece area portion inclin\$6))) and "73"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/02/07 10:50